

NOVA MEASURING INSTRUMENTS LTD.

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Website www.nova.co.il
Year established: 1993
Contact person: Dr. Moshe Finarov, CTO

Ownership: Public

Core Business:

Computerized electro-optical measuring instruments for controlling production of semiconductors. Integrated process control systems in the semiconductor manufacturing industry.

Total number of employees: 220
Scientists and engineers: 150
Annual turnover (Thousands US \$): 20400

Overview:

NOVA MEASURING INSTRUMENTS LTD. develops, produces and markets monitoring and measurement systems for the semiconductor manufacturing industry.

The company, founded in 1993, has pioneered the Integrated Metrology concept and is now expanding its activities by developing Integrated Monitoring and Process Control systems for CMP, CVD, Photolithography and Etch manufacturing processes. The company's Integrated Thickness Monitoring (ITM) systems for CMP process control, delivering an unequaled degree of wafer-to-wafer Closed Loop Control, have measured more wafers than all other metrology companies combined.

The new developments of the company are based on the existing integrated technological platform and the broad field experience of the company. Nova has established OEM partnerships with the major CMP tool manufacturers. They make their systems "NovaReady" by finding on-tool space and providing wafer handling access and minimal wiring for the ITM system which is a little larger than a wafer, with a small optical head that scans the wafers. Applied Materials, Ebara, Peter Wolters, SpeedFam-IPEC, Steag, Strasbaugh, and others have made their systems "NovaReady", making the installation of Nova's ITM systems a simple "plug-and-play" process. Nova is strongly committed to its multi-vendor policy and is establishing relationships with different process equipment manufacturers for its new developments.